TOSHIBA Field Effect Transistor Silicon N Channel Junction Type

2SK881

FM Tuner Applications VHF Band Amplifier Applications

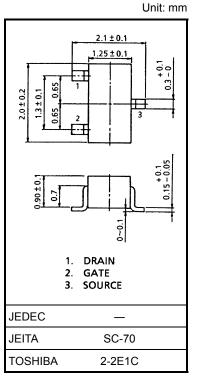
- Low noise figure: NF = 2.5dB (typ.) (f = 100 MHz)
- High forward transfer admittance: $|Y_{fs}| = 9 \text{ mS (typ.)}$

Absolute Maximum Ratings (Ta = 25°C)

Characteristics	Symbol	Rating	Unit
Gate-drain voltage	V_{GDO}	-18	٧
Gate current	IG	10	mA
Drain power dissipation	P _D	100	mW
Junction temperature	Tj	125	°C
Storage temperature range	T _{stg}	-55~125	°C

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

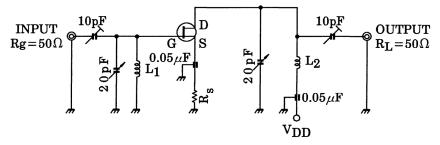


Weight: 0.006 g (typ.)

Electrical Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current	I _{GSS}	$V_{GS} = -0.5 V, V_{DS} = 0$	_	_	-10	nA
Gate-drain breakdown voltage	V (BR) GDO	$I_G = -10 \mu A$	-18	_	_	V
Drain current	I _{DSS} (Note)	V _{GS} = 0, V _{DS} = 10 V	1.0	_	10	mA
Gate-source cut-off voltage	V _{GS (OFF)}	$V_{DS} = 10 \text{ V}, I_D = 1 \mu\text{A}$	-0.4	_	-4.0	V
Forward transfer admittance	Yfs	$V_{GS} = 0$, $V_{DS} = 10 \text{ V}$, $f = 1 \text{ kHz}$	_	9	_	mS
Input capacitance	C _{iss}	$V_{DS} = 10 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$	_	6.0	_	pF
Reverse transfer capacitance	C _{rss}	$V_{DS} = 10 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$	_	_	0.15	pF
Power gain	G _{ps}	V _{DD} = 10 V, f = 100 MHz (Figure 1)	10	18	_	dB
Noise figure	NF	V _{DD} = 10 V, f = 100 MHz (Figure 1)	_	2.5	3.5	dB

Note: IDSS classification O: 1.0~3.0, Y: 2.5~6.0, GR: 5.0~10.0



 $L_1{:}~0.8~\text{mm}_{\varphi}~\text{A}_g$ plated Cu wire, 3 turns, 10 mm ID, 10 mm length.

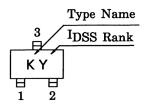
 $L_2{:}~0.8~mm\varphi~A_g$ plated Cu wire, 3.5 turns, 10 mm ID, 10 mm length.

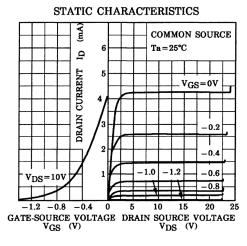
Figure 1 100 MHz G_{PS}, NF Test Circuit

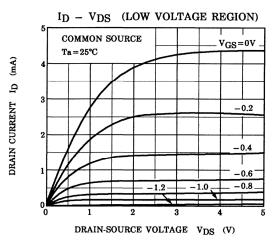
2SK881 is measured at each group by changing $R_{\rm s}.$

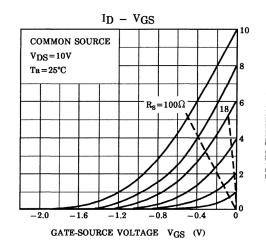
Group	R _S (Ω)	
2SK881-O	0	
2SK881-Y	18 $\Omega \pm 5\%$	
2SK881-GR	100 $\Omega \pm 5\%$	

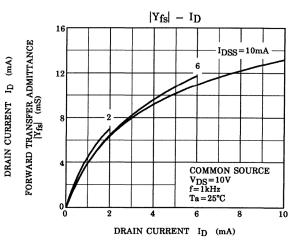
Marking

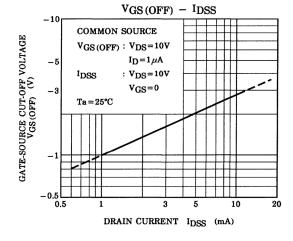


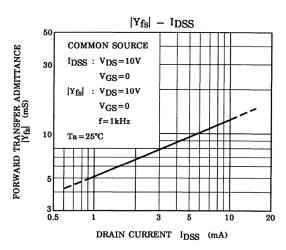


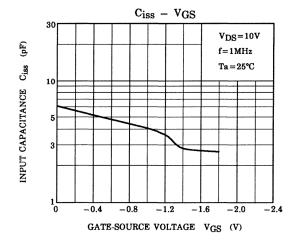


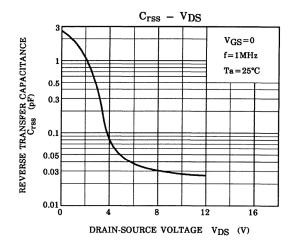


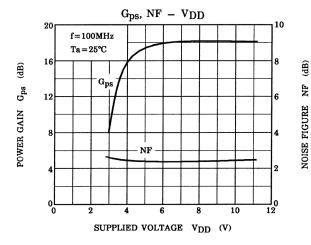


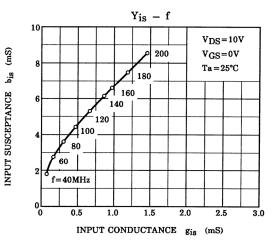


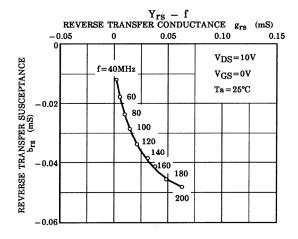


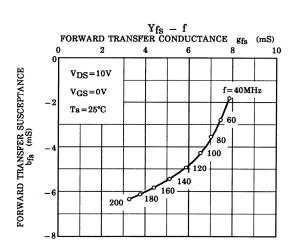


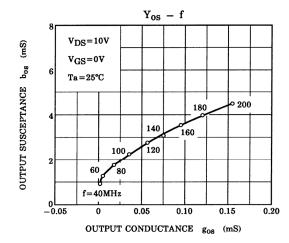


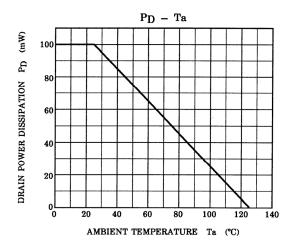












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